

<b>Notice of References Cited</b>	Application/Control No. 10/501,165	Applicant(s)/Patent Under Reexamination ANTON APETZ ET AL.	
	Examiner Hana A. Sanei	Art Unit 2879	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,020,685	02-2000	Wei et al.	313/625
	B	US-4,076,898	02-1978	McVey, Charles I.	428/553
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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